

4/13/04

SHEET 1 OF 1

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

251445US2S CONT

SERIAL NO.

New Cont Application

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Toshimasa NAMEKAWA, et al.

FILING DATE

Herewith

GROUP

Unassigned

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
ap	AA	5,740,099	04/1998	Tanigawa			
ap	AB	6,483,749	11/2002	Choi et al.			
ap	AC	6,310,505	10/2001	Ogawa et al.			
ap	AD	5,946,268	08/1999	Iwamoto et al.			
ap	AE	5,768,177	06/1998	Sakuragi, Shinji			
	AF						
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO					
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	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

ap	AW	Paul DeMone, et al., "A 6.25ns Random Access 0.25 μ m Embedded DRAM", 2001 Symposium on VLSI Circuits Digest of Technical Papers, 4-89114-013-5
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

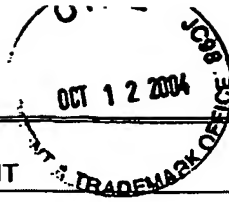
Chue Phuong

Date Considered 12/5/05

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 251445US2SCONT		SERIAL NO. 10/822,673	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Toshimasa NAMEKAWA, et al.			
				FILING DATE April 13, 2004		GROUP 2818	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>CP</i>	AO	4-30385	02/03/1992	JAPAN		X	
	AP	11-238860	08/31/1999	JAPAN		X	
	AQ	2001-274236	10/05/2001	JAPAN		X	
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
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Examiner <i>Chh Phung</i>					<input type="checkbox"/> Additional References sheet(s) attached		
					Date Considered <i>12/5/05</i>		
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Form PTO 1449 (1-10-03)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 251445US2S CONT		SERIAL NO. 10/822,673	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Toshimasa NAMEKAWA, et al.			
				FILING DATE April 13, 2004		GROUP 2818	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
AP	AO	2-218159	08/30/1990	JAPAN			X
	AP						
	AQ						
	AR						
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
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Examiner <i>Cash Pheng</i>					<input type="checkbox"/> Additional References sheet(s) attached		
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(Mod. 5-04)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
251445US2SCONTSERIAL NO.
10/822,673

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Toshimasa NAMEKAWA, et al.

FILING DATE
April 13, 2004GROUP
2818

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	6,333,532 B1	12/25/2001	Bijan DAVARI, et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
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